

**Notice of References Cited**

Application/Control No.

10/534,819

Applicant(s)/Patent Under  
Reexamination  
UEDA ET AL.

Examiner

Madeleine AV Nguyen

Art Unit

2625

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,666,215 A	09-1997	Fredlund et al.	358/487
*	B	US-2002/0047905 A1	04-2002	Kinjo, Naoto	348/207
*	C	US-6,614,454 B1	09-2003	Livingston, Kris R.	715/781
*	D	US-2005/0122541 A1	06-2005	Tanimura, Masayoshi	358/001.16
*	E	US-2007/0002175 A1	01-2007	Narushima et al.	348/552
*	F	US-2008/0010168 A1	01-2008	Kinjo, Naoto	705/026
*	G	US-2008/0044055 A1	02-2008	Kinjo, Naoto	382/100
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.